



Development and Calibration of the ART-XC Mirror Modules for the Spectrum Rontgen Gamma Mission



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SRG Overview



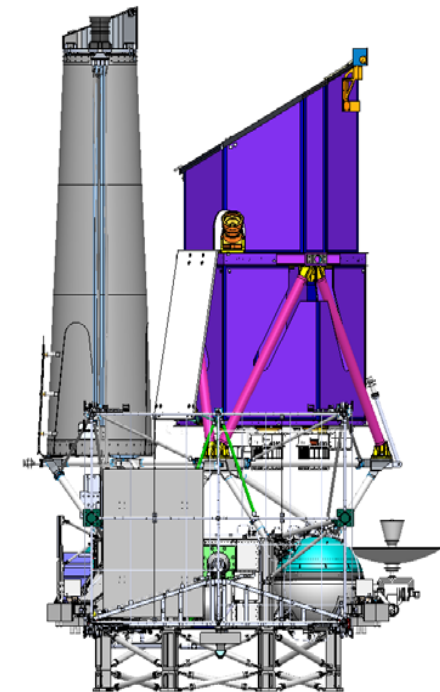
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- ✓The Spectrum-Röntgen-Gamma (SRG) mission is a Russian-lead X-ray astrophysical observatory that carries two co-aligned X-ray telescope systems.
- ✓The primary instrument is the German-led **extended ROentgen Survey with an Imaging Telescope Array** (eROSITA), a 7-module X-ray telescope system that covers the energy range from 0.2-12 keV.
- ✓The complementary instrument is the **Astronomical Roentgen Telescope – X-ray Concentrator** (ART-XC or ART), a 7-module X-ray telescope system that provides higher energy coverage, up to 30 keV.

Parameter	ART	eROSITA
Energy Range	5-30 keV	0.2-12 keV
Effective Area	455 cm ² at 8 keV	2500 cm ² at 1 keV
Field of View	32 arcmin	1 deg
System Angular Resolution (on axis)	1 arcmin	15 arcsec
Energy Resolution	1.4 keV at 14 keV	130 eV at 6 keV

ART-XC

eROSITA





ART-XC Optics Configuration



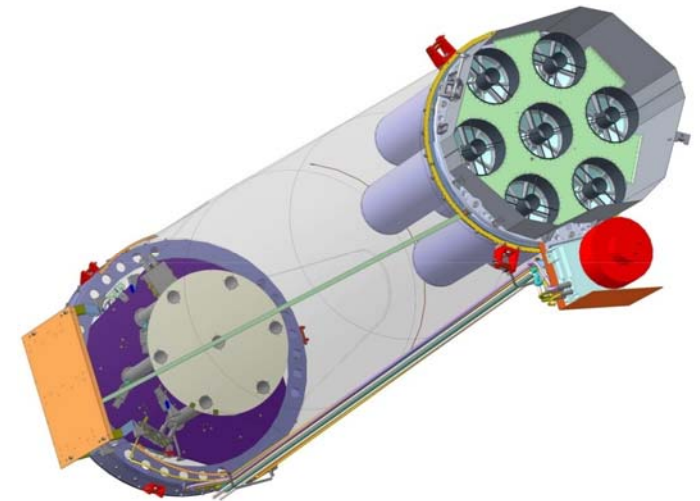
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MSFC has designed and is fabricating

➤ **four** ART x-ray optics modules under an International Reimbursable Agreement between NASA and with IKI (delivery – February 2014)

➤ **three + one spare** ART modules under Agreement regarding Cooperation on the ART-XC Instrument onboard the SRG Mission between NASA and IKI (delivery – March 2014)

Parameter	Value
Number of Mirror Modules	7=4+3
Number of Shells per Module	28
Shell Coating	> 10 nm of iridium (> 90% bulk density)
Shell Total Length, inner and outer diameters	580 mm, 50 mm, 150 mm
Encircled Half Energy Width	Less than 1 mm diameter, center of field of view Less than 2.5 mm diameter, 15 arcmin off axis
Mirror Module Effective Area	$\geq 65 \text{ cm}^2$ at 8 keV (on axis)
Module Focal Length	2700 $\pm$ 1 mm



Schematic representation of the ART-XC instrument

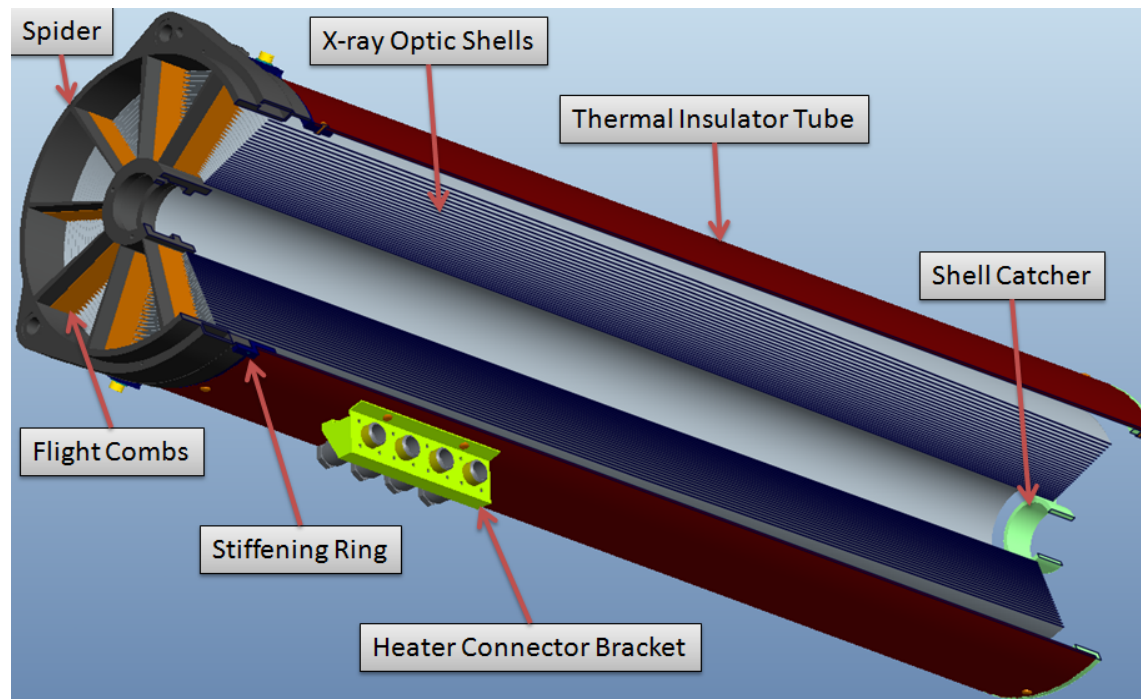




Mechanical Design



- One spider design permits increasing the thickness of outer shells for given weight budget (15 kg / Module)
- Shells are electroformed NiCo, 250 – 325 microns thick

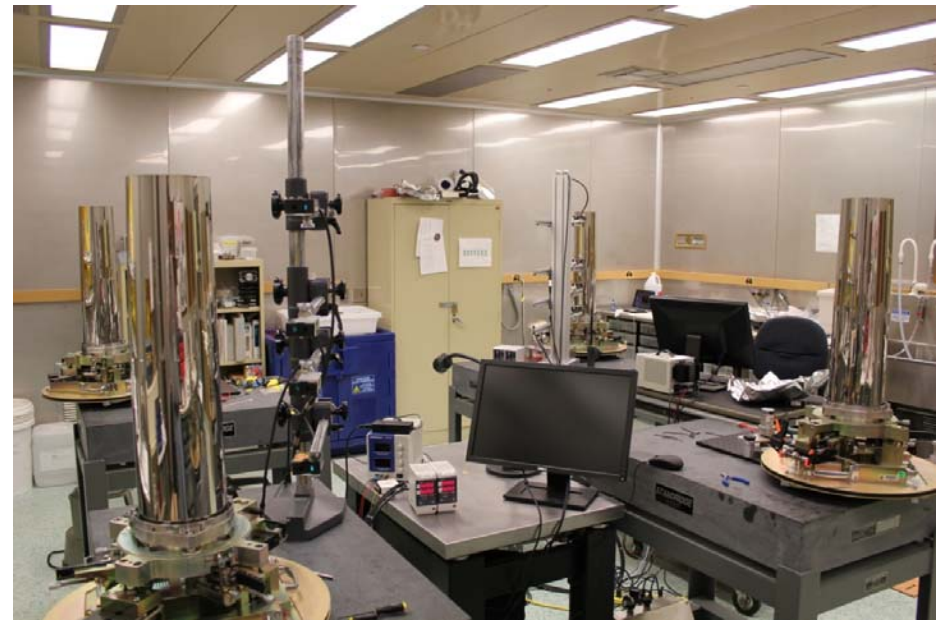




ART-XC Mirror Production



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ART-XC Mirror Status



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- All shells fabricated for 1st four module
- 75% of shells fabricated for 2nd four modules
- Qualification (engineering) unit tested and delivered to IKI
- 1st flight module undergone extended x-ray calibration
- 2nd module under calibration now



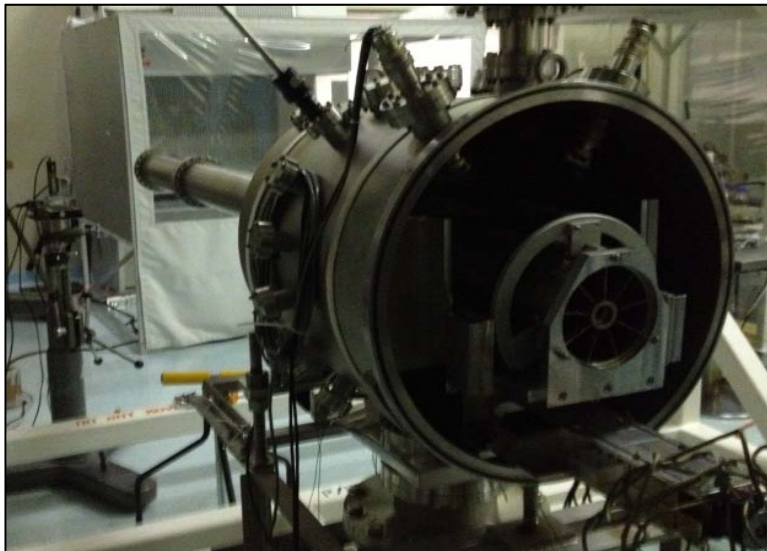


ART-XC: MSFC Test Facility



MSFC STRAY LIGHT FACILITY

- ~ 104 m Beamline
- 1-m diameter main tube
- 3m x 10m instrument chamber
- **FOR ART testing:**
- Bell housing for smaller, shorter-focal-length optics
- Contains Tip, Yaw and linear stages all computer controlled
- Cu x-ray source system, 50kV, 1 mA, 0.5 mm spot



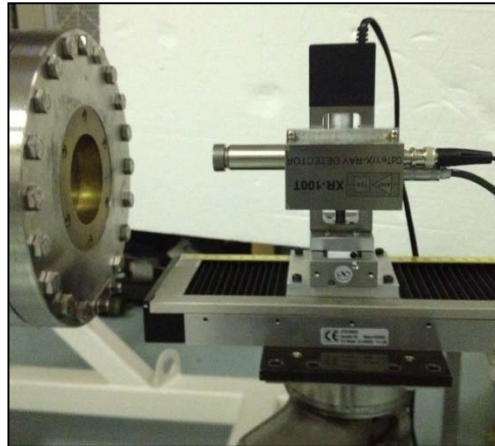


ART-XC: MSFC Test Facility



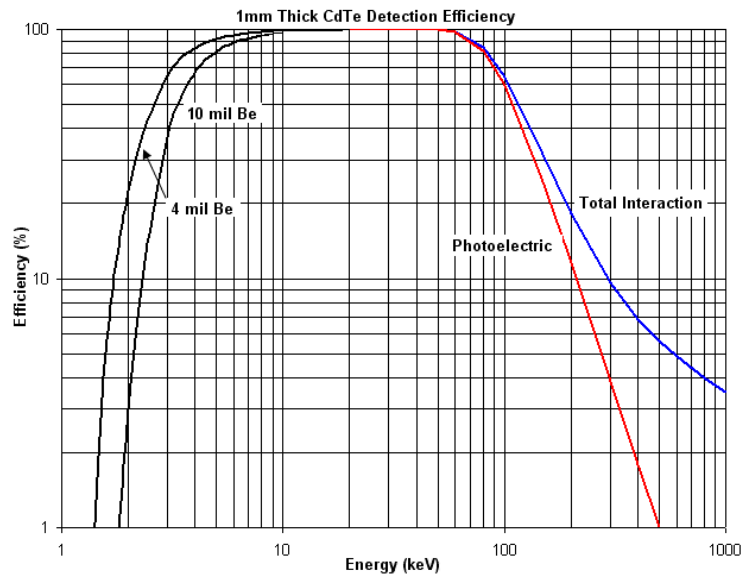
CdTe Detector

- 5 x 5 x 1 mm
- High rate capability (>105 c/s)
- Series of laser-cut W pinholes



CCD Camers

- 2k x 2k pixels
- 13.5 micron each
- Frame / sec readout capability

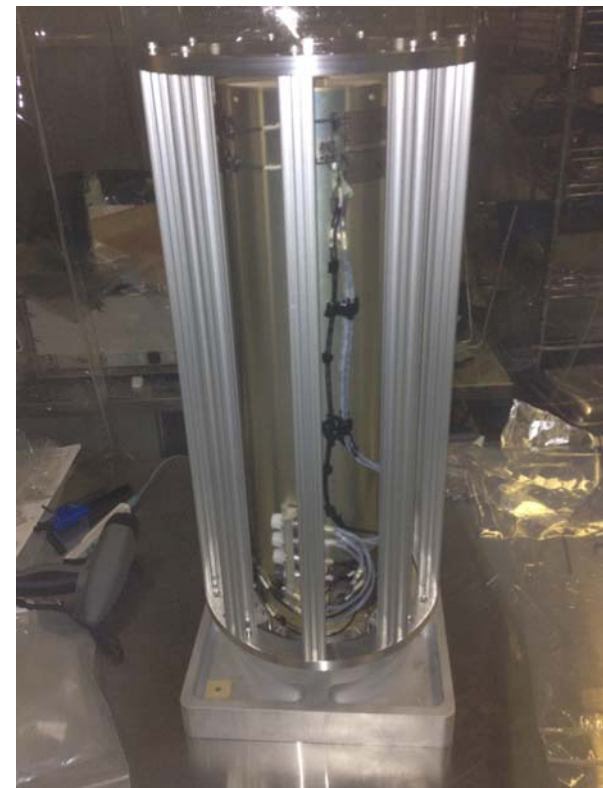
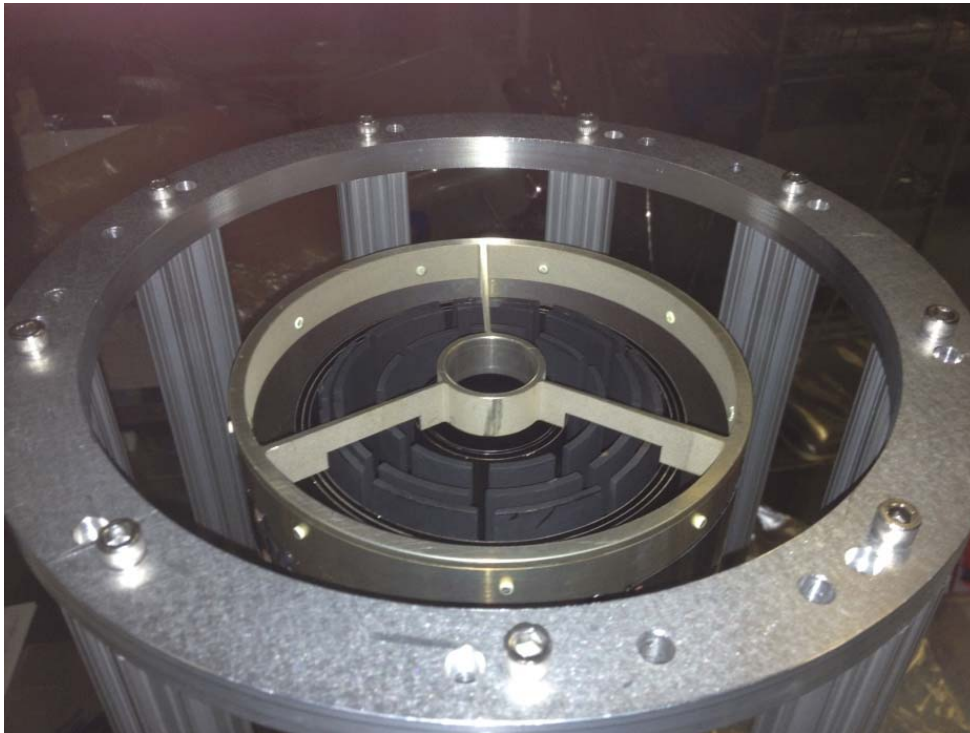




Qualification Unit



- ✓ Three inner shells (1,2,4)
- ✓ Three outer shells (25,26,27)
- ✓ Three mass simulators to replace missing shells (diameters are 74, 101.3 and 126.4 mm)



Qualification unit with handling fixture mounted on the shipping base



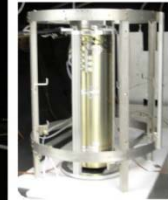
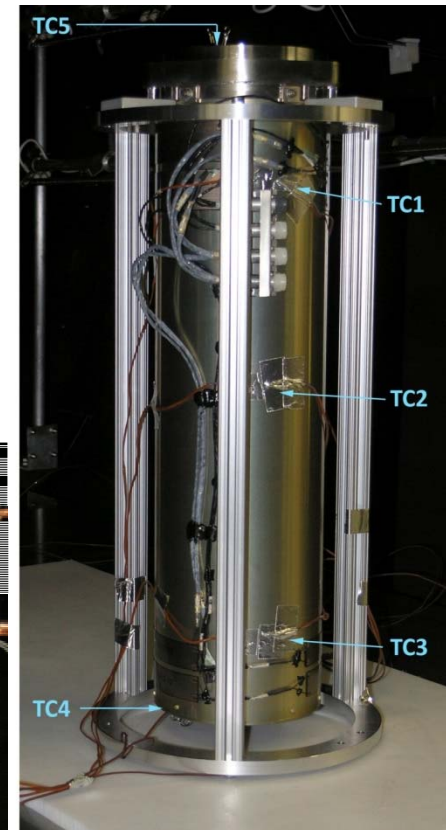
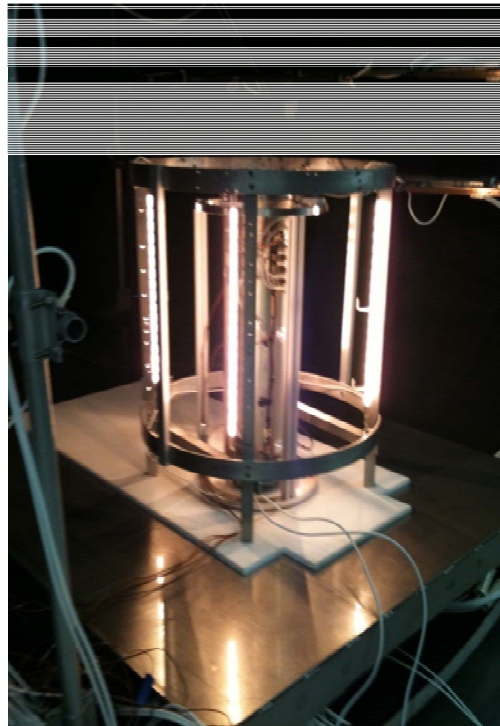
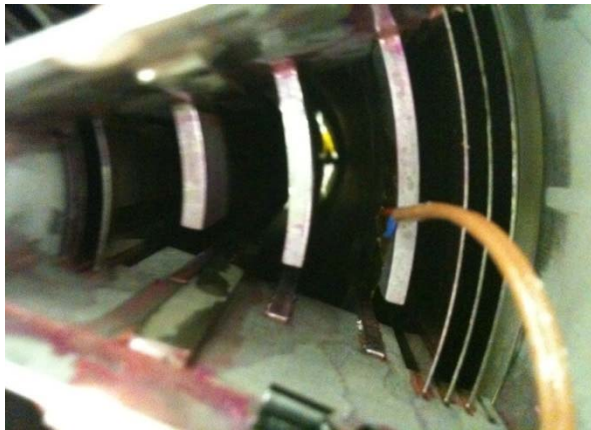


ART-XC: Qualification Unit

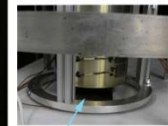


Effective area and resolution of qualification unit measured as follows:

- Initial test
- Post vibration test #1
- Post thermal (survival temperatures) test
- Post acoustic test
- Post module modification (stabilizers added)
- Post vibration test #2
- Final (post shock test)



With Lamp Array



OWS

ART-XC X-ray Module
Thermal Cycle Test
ET20-2013-686
March 13, 2013
Chamber V7

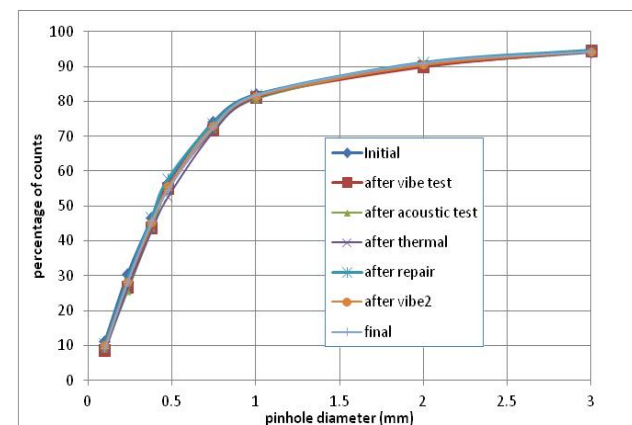


ART-XC: Qualification Unit X-ray Results

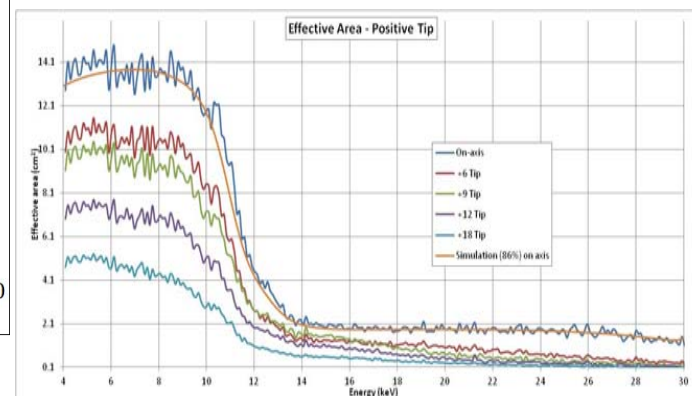
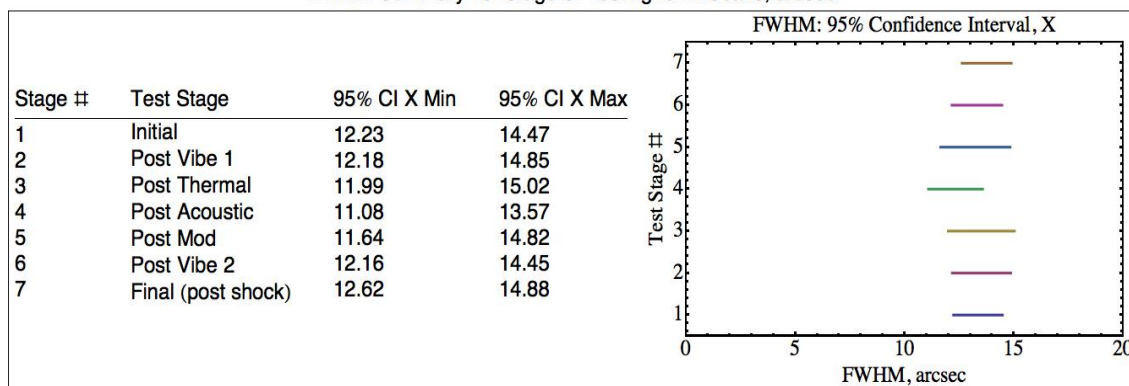


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Test	Effective Area (cm ²)	Error (cm ²)
Initial	13.56	0.35
Post vibration test # 1	13.26	0.49
Post thermal test	13.01	0.47
Post acoustic test	13.81	0.38
Post module modification (stabilizers)	Not tested	
Post vibration test # 2	13.49	0.38
Final (post shock)	13.71	0.38



FWHM Summary vs. Stage of Testing for X Scans, arcsec





Flight Unit X-ray Calibration Requirements



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CCD CAMERA

Point Spread Function (PSF) – FIRST MODULE

Measure the PSF at each focus position and off-axis angle listed below:

NOMINAL FOCUS

Offset angles (36 measurements)

Range: -18, -12, -7, -3, 0, 3, 7, 12, 18 arcmin at four different azimuthal angles: 0, 45, 90, 135

NOMINAL – 7 MM

Offset angles (68 measurements)

Range: -18, -15, -12, -9, -7, -5, -3, -1, 0, 1, 3, 5, 7, 9, 12, 15, 18 arcmin at four different azimuthal angles: 0, 45, 90, 135

NOMINAL – 15 MM

Offset angles (36 measurements)

Range: -18, -12, -7, -3, 0, 3, 7, 12, 18 arcmin at four different azimuthal angles: 0, 45, 90, 135

Point Spread Function (PSF) – REMAINING MODULES

Measure the PSF at each off-axis angle listed below:

NOMINAL – 7 MM

Offset angles (68 measurements)

Range: -18, -15, -12, -9, -7, -5, -3, -1, 0, 1, 3, 5, 7, 9, 12, 15, 18 arcmin at four different azimuthal angles: 0, 45, 90, 135

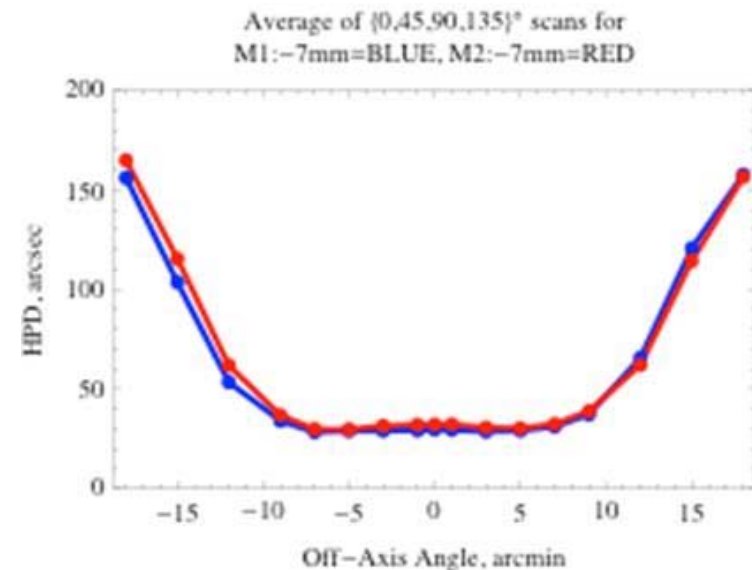
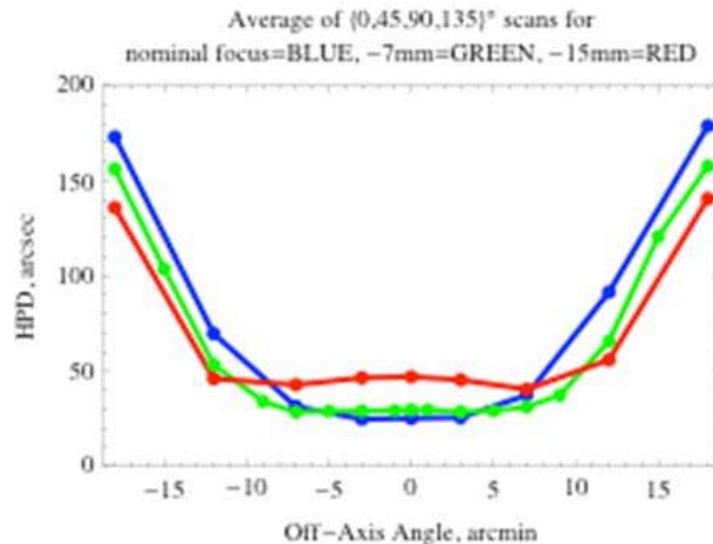




Flight Unit X-ray Calibration (CCD)

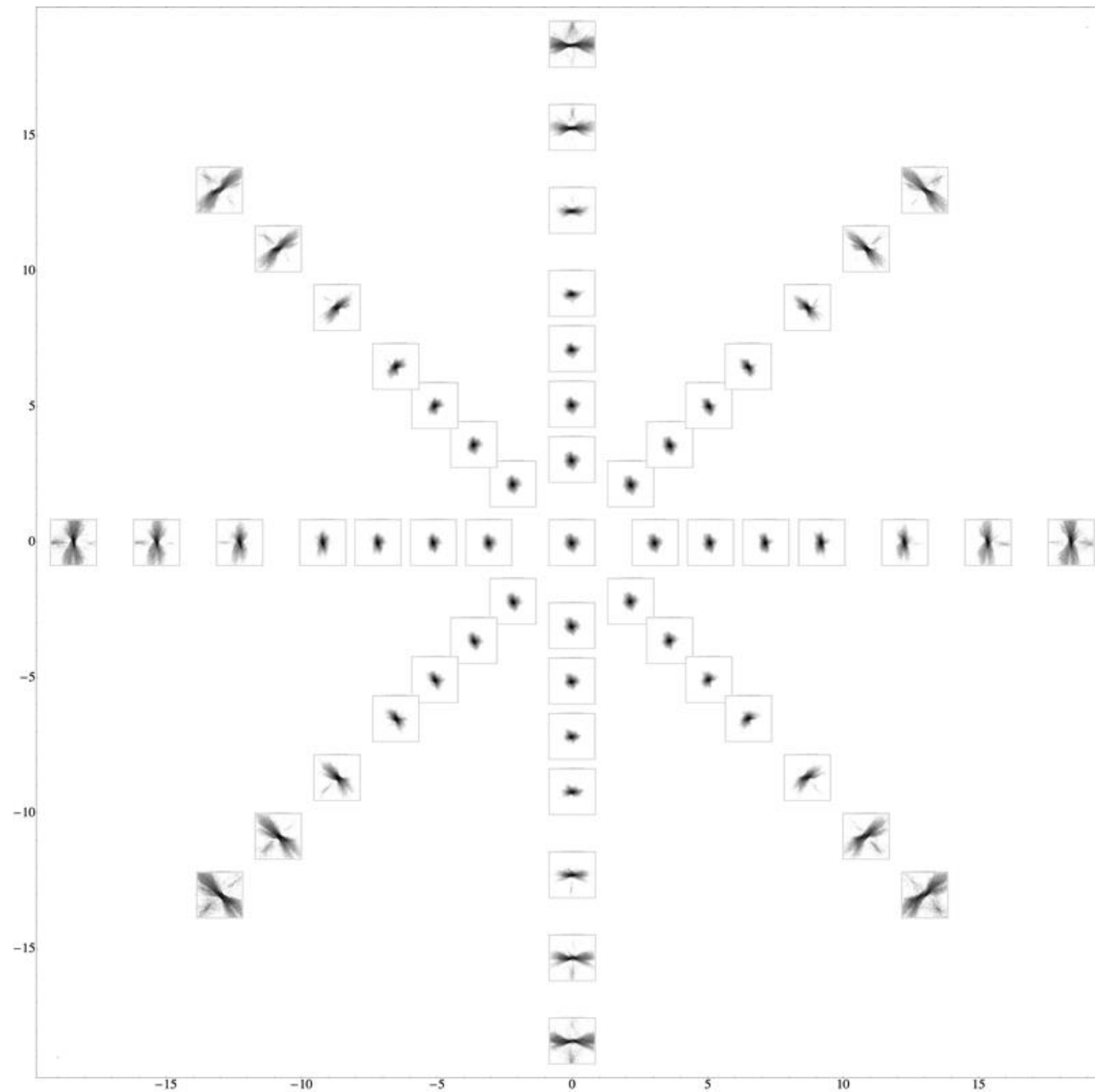


- M1 Half Power Diameter vs. Off-Axis Angle for Several Focus Positions
 - Field of view with HPD < flight pixel size expands with de-focus
 - 7 mm defocus position is preferred for flight for best survey sensitivity
- M1 vs. M2 Half Power Diameter vs. Off-Axis Angle at Preferred Focus Position
 - Modules are very similar
 - Repeatability of calibration results confirmed





Flight Unit X-ray Calibration (CCD)



True-to-scale images
at 7mm from focus, as
a function of off-axis
angle in arcmin





Flight Unit X-ray Calibration (CCD)

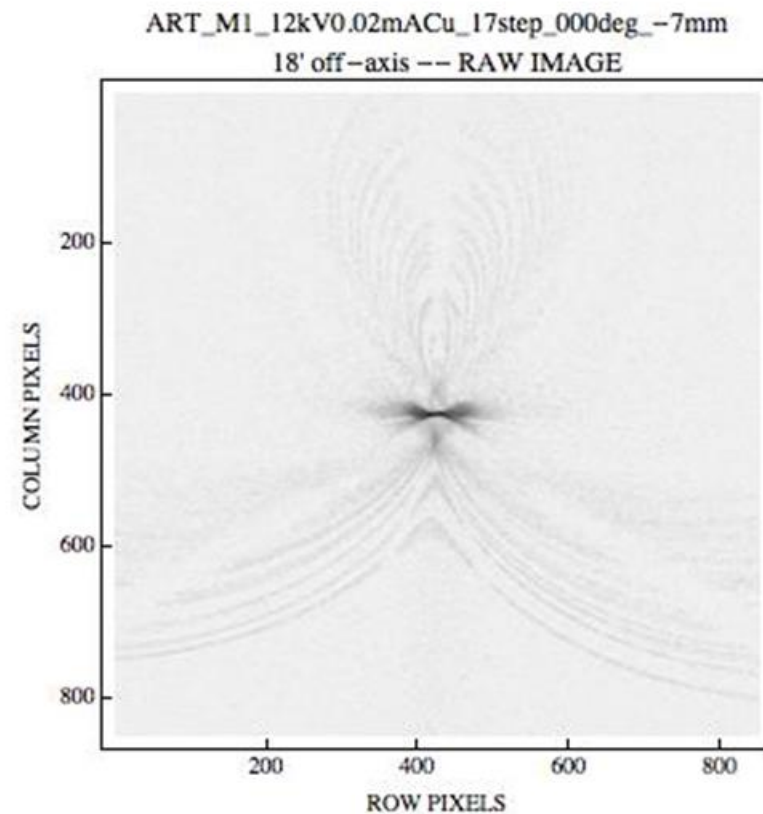
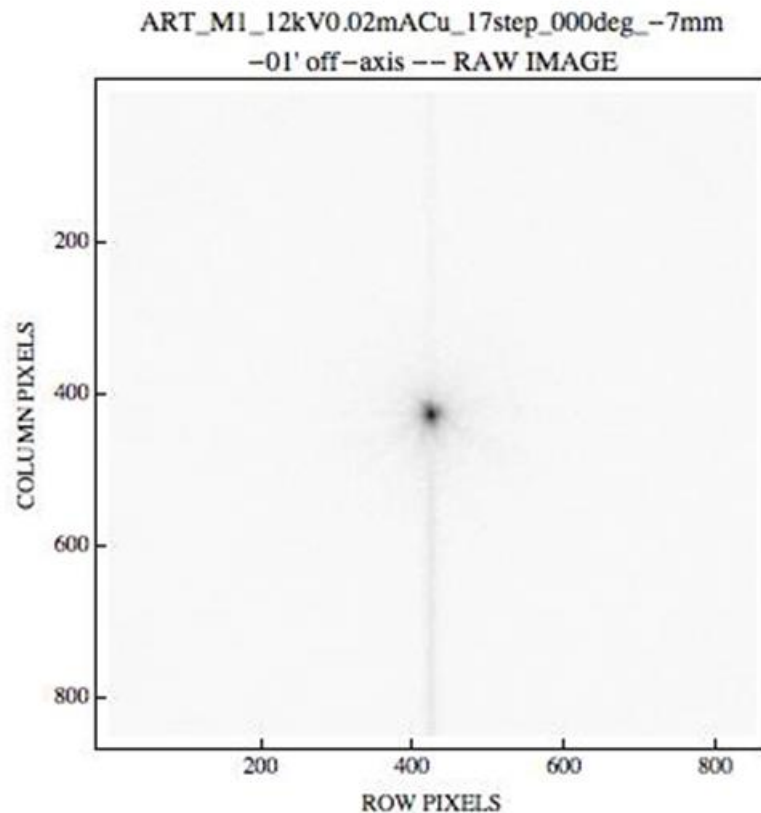
Comparison of on-axis and 18 arcmin off-axis raw images

Off-axis image shows extended wing structure due to singly reflected x-rays

Vertical line below on-axis image is an artifact of CCD readout smear -- removed in analysis

X-rays from 8 keV Cu-K lines

1 pixel = 2 arcsec

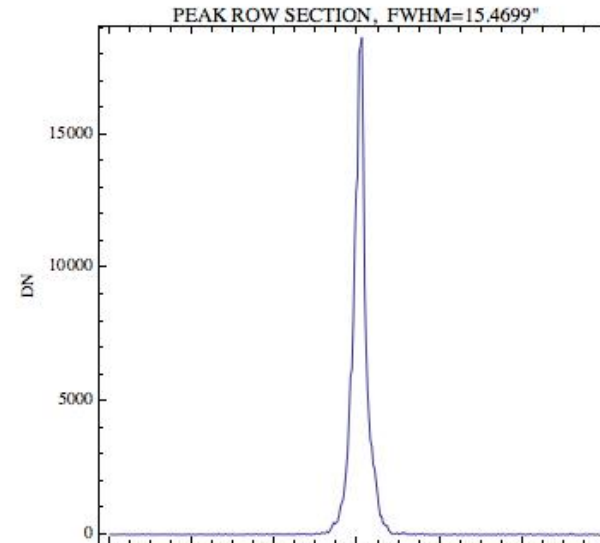
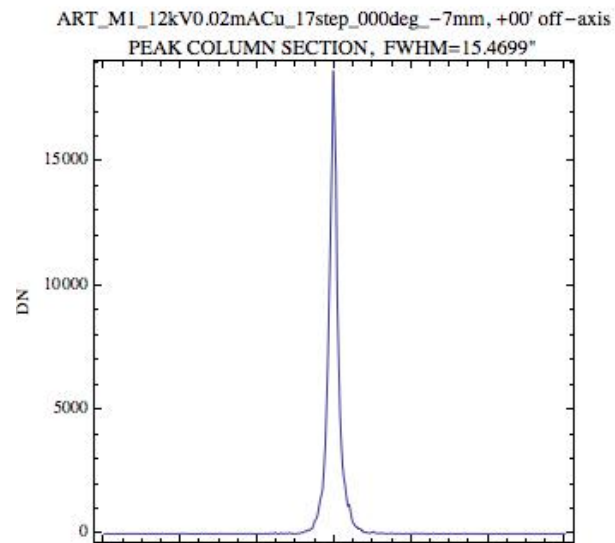




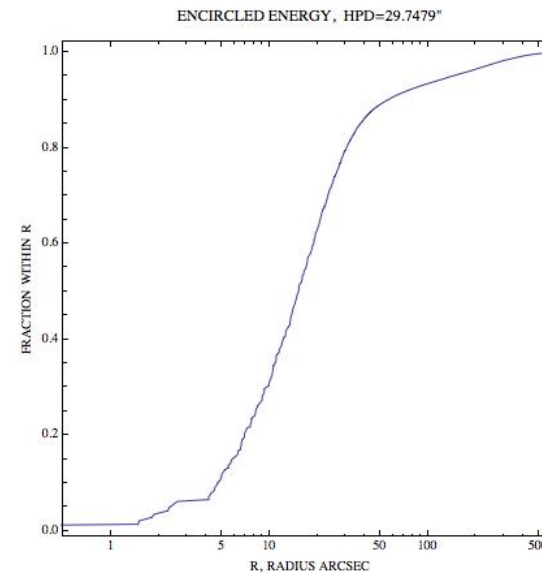
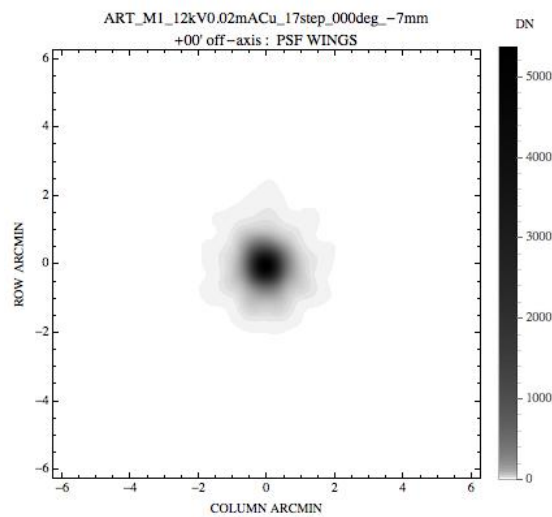
Flight Unit X-ray Calibration (CCD)



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FWHM on axis



PSF on axis

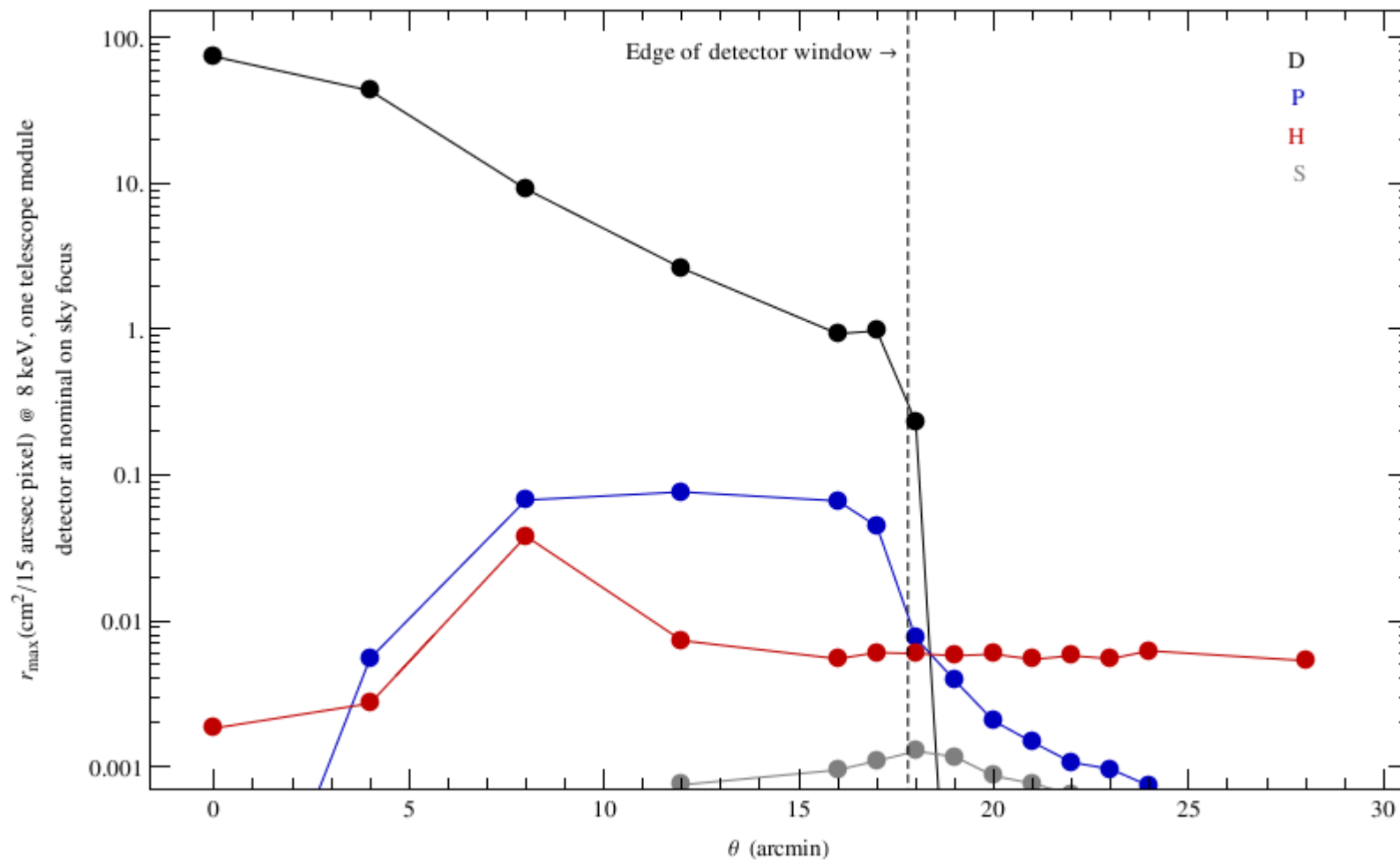


Modeled Stray Light



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Modeled stray light reaching the detector on orbit, in terms of brightest pixel. Curves represent (double reflected (black) and singles from the P (blue) and H (red) segments. Straight-throughs are depicted in gray.

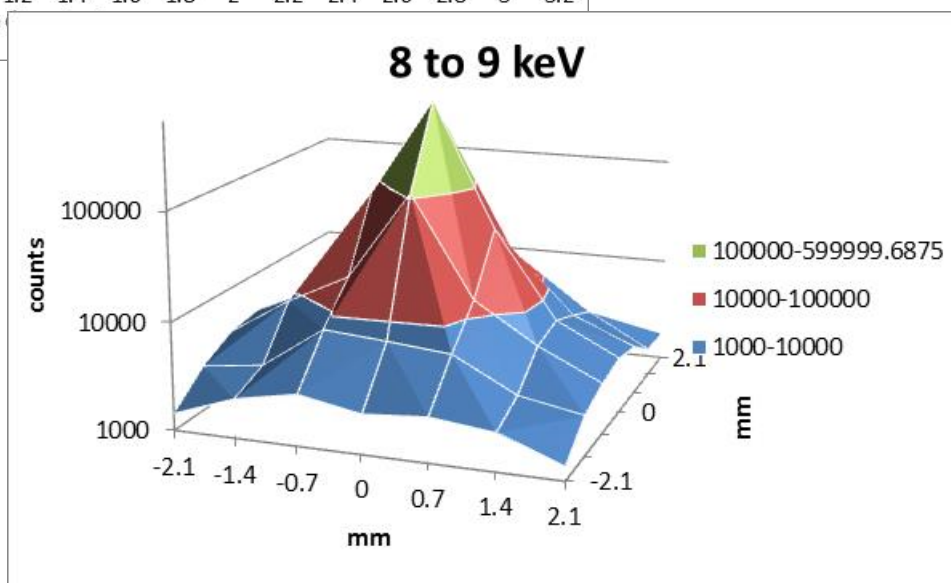
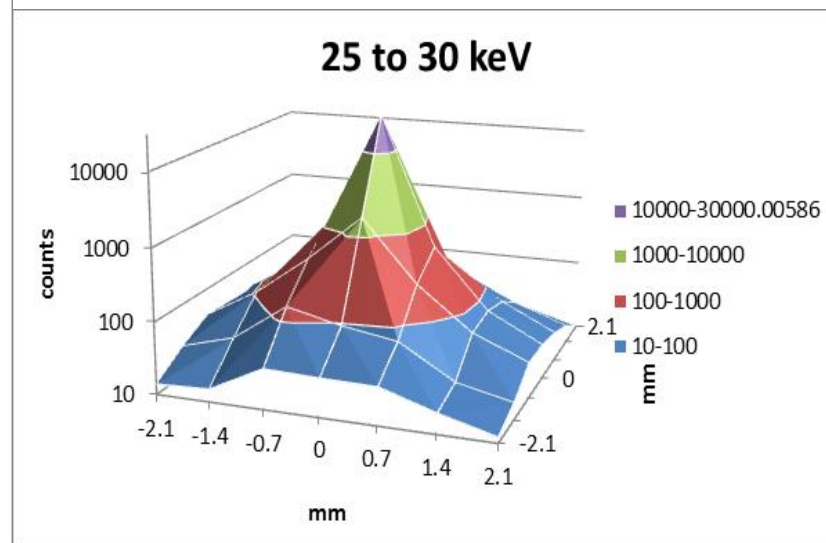
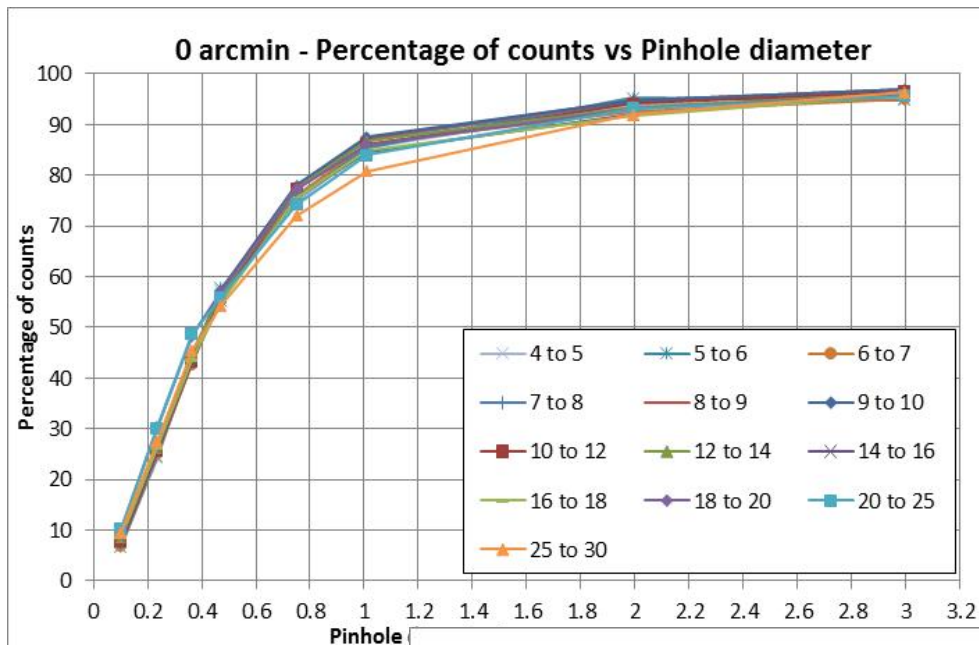




Flight Unit X-ray Calibration (CdTe)



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On axis
measurements



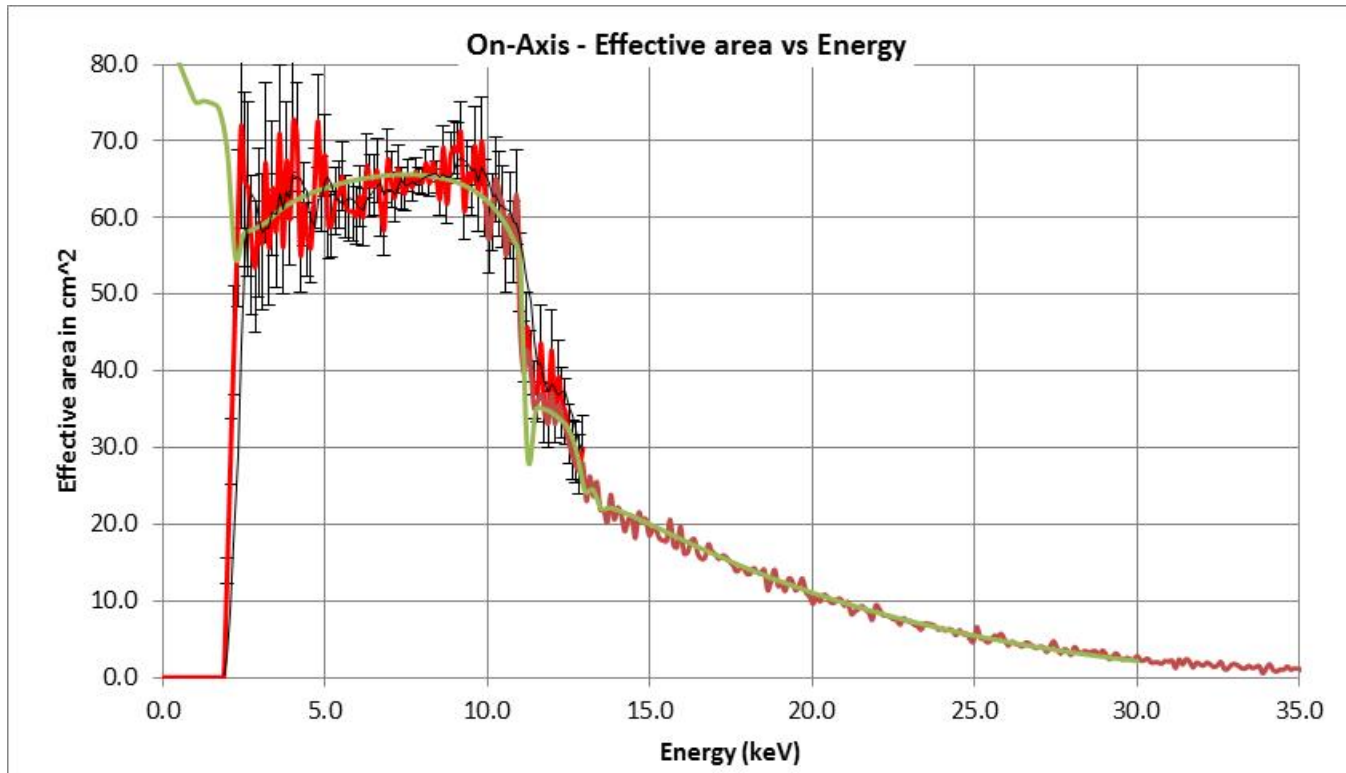
IRI



Flight Unit X-ray Calibration (CdTe)



Flight Module 2 measured effective area (104m) compared with (91%) model

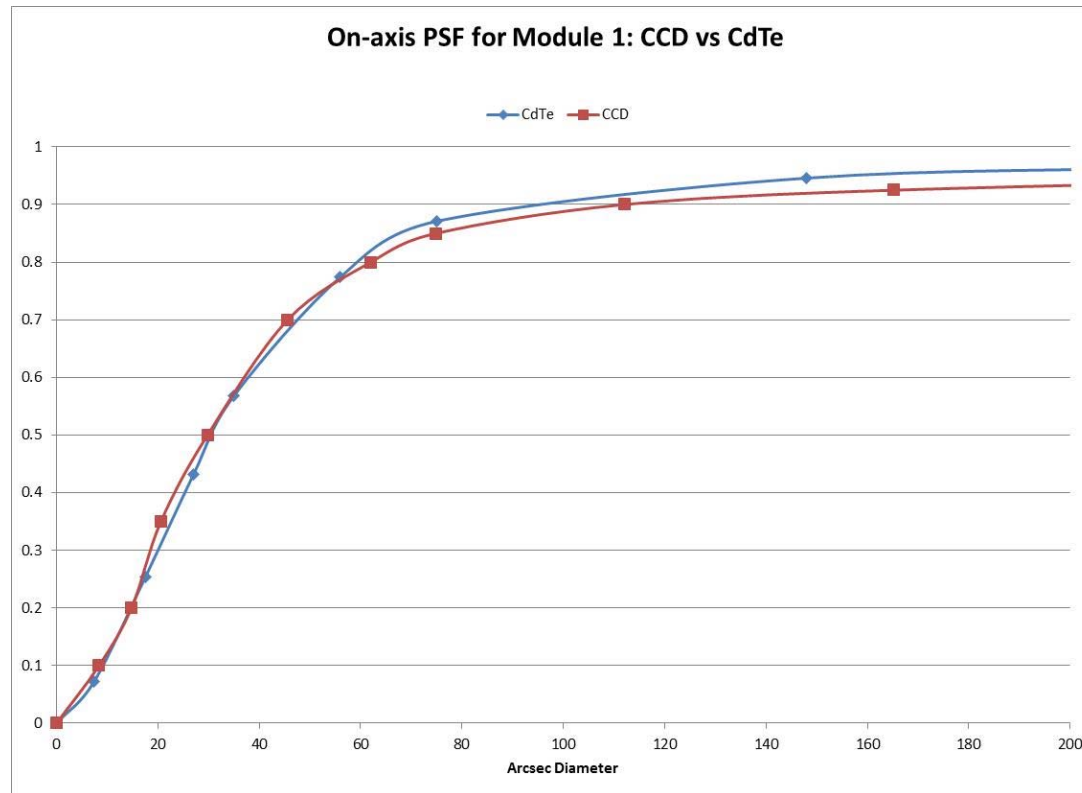


On-axis effective area (infinite source) = 68 cm^2 (requirement = 65 cm^2)





Flight Unit X-ray Calibration (Comparison)



Reasonably good agreement between CCD and CdTe





Flight Unit X-ray Calibration: CONCLUSION

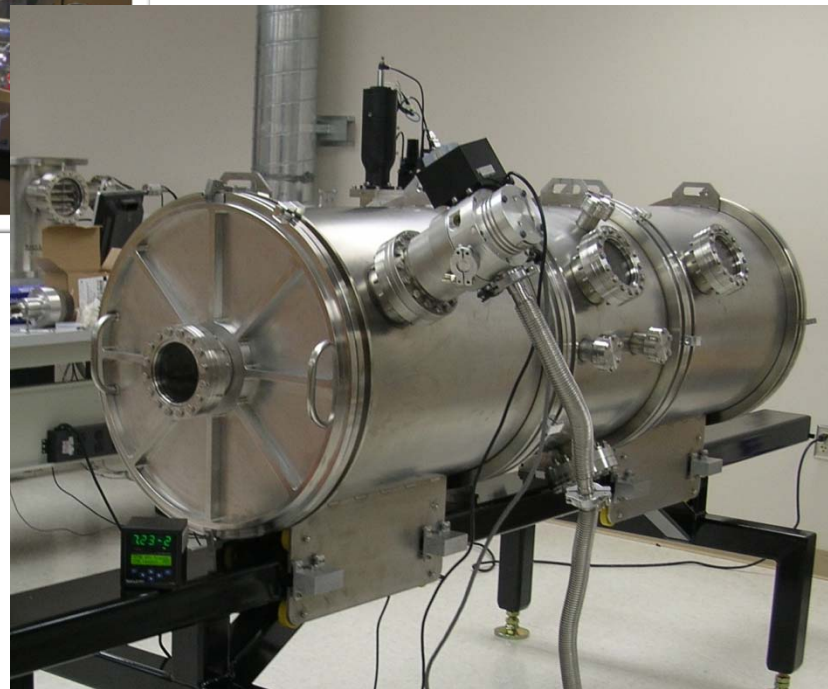
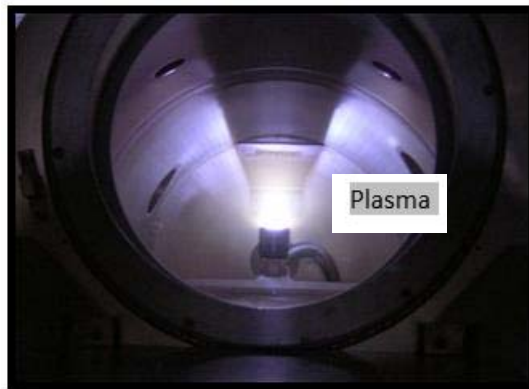
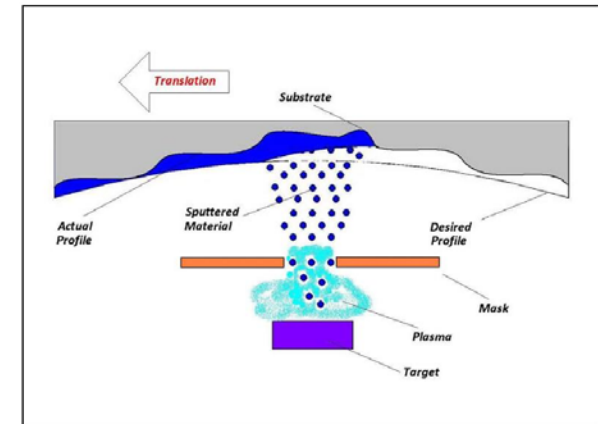


- ART-XC Flight Module Calibration and data processing has begun
- CCD and CdTe data agree well
- The first two modules meet effective area requirement (65 cm^2 / module @ 8 keV) and greatly exceed angular resolution requirement (30 arcsec, defocused, vs ~ 60 arcsec)
- Calibration will be concluded by late February / early March 2014





Differential Deposition (K.Kilaru, C. Atkins, D. Broadway)





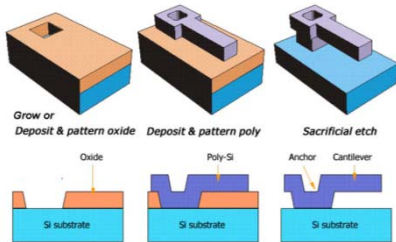
Stress Measurement in Coatings (D. Broadway)



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Methods of In-Situ Stress Measurement: All aim to measure the change in curvature

of the substrate from which stress is calculated from the Stoney equation: $\sigma h_{film} = M \frac{h^2}{6} \kappa$



Our Method: We exploit the known spherical deformation and infer the substrate curvature by measuring the sag of the wafer (just one point).

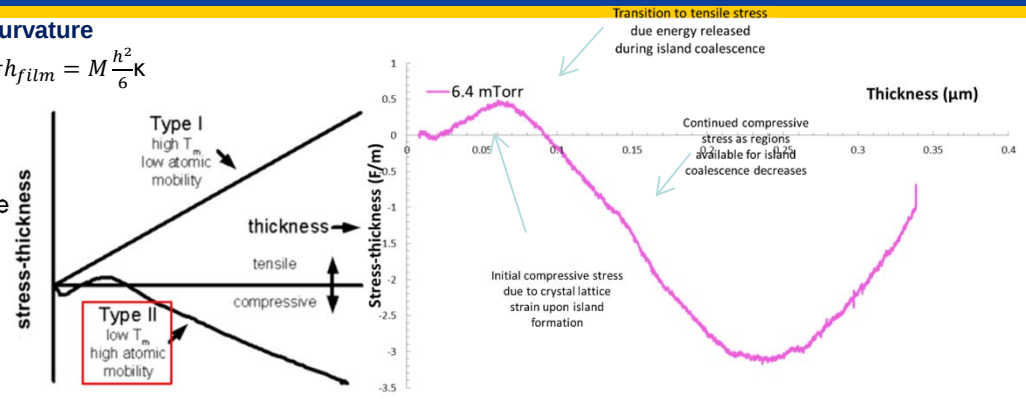
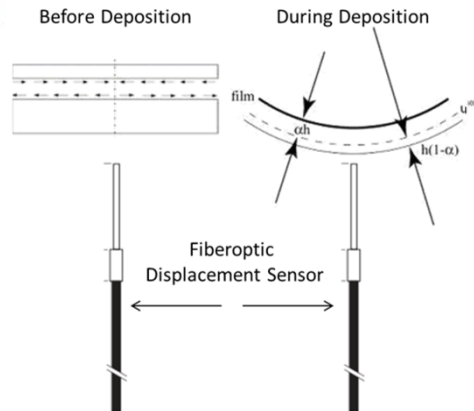
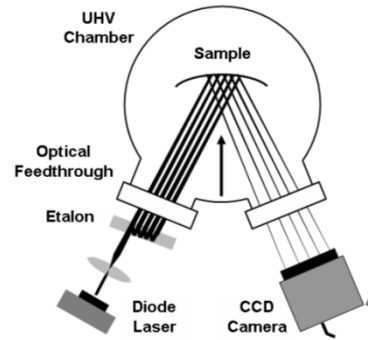


Figure 1- After R. Abermann, Vacuum 41, 1279 (1990) (left); Measured In-Situ (right)- Data matches measured curves from several published experiments.

